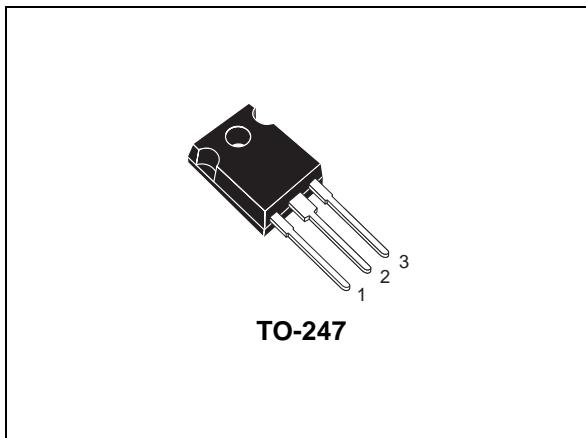
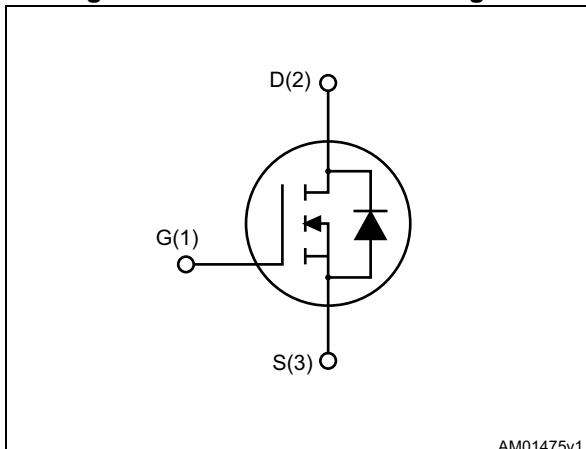


## N-channel 500 V, 0.035 Ω, 68 A, MDmesh™ II Power MOSFET in a TO-247 package

Datasheet - production data



**Figure 1. Internal schematic diagram**



### **Features**

Order code	$V_{DSS}$ (@ $T_{jmax}$ )	$R_{DS(on)}$ max	$I_D$
STW60NM50N	550 V	<0.043 Ω	68 A

- 100% avalanche tested
- Low input capacitance and gate charge
- Low gate input resistance

### **Applications**

- Switching applications

### **Description**

This device is an N-channel Power MOSFET developed using the second generation of MDmesh™ technology. This revolutionary Power MOSFET associates a vertical structure to the company's strip layout to yield one of the world's lowest on-resistance and gate charge. It is therefore suitable for the most demanding high efficiency converters.

**Table 1. Device summary**

Order codes	Marking	Packages	Packaging
STW60NM50N	60NM50N	TO-247	Tube

# 1 Electrical ratings

**Table 2. Absolute maximum ratings**

Symbol	Parameter	Value	Unit
$V_{GS}$	Gate- source voltage	$\pm 25$	V
$I_D$	Drain current (continuous) at $T_C = 25^\circ\text{C}$	68	A
$I_D$	Drain current (continuous) at $T_C = 100^\circ\text{C}$	43	A
$I_{DM}^{(1)}$	Drain current (pulsed)	272	A
$P_{TOT}$	Total dissipation at $T_C = 25^\circ\text{C}$	446	W
$dv/dt^{(2)}$	Peak diode recovery voltage slope	15	V/ns
$T_{stg}$	Storage temperature	-55 to 150	$^\circ\text{C}$
$T_j$	Max. operating junction temperature	150	$^\circ\text{C}$

1. Pulse width limited by safe operating area.
2.  $I_{SD} \leq 68$  A,  $di/dt \leq 400$  A/ $\mu\text{s}$ ,  $V_{DD} = 80\%$   $V_{(BR)DSS}$

**Table 3. Thermal data**

Symbol	Parameter	Value	Unit
$R_{thj-case}$	Thermal resistance junction-case max	0.28	$^\circ\text{C}/\text{W}$
$R_{thj-amb}$	Thermal resistance junction-ambient max	50	$^\circ\text{C}/\text{W}$

**Table 4. Avalanche characteristics**

Symbol	Parameter	Value	Unit
$I_{AS}$	Avalanche current, repetitive or not-repetitive (pulse width limited by $T_{j Max}$ )	11	A
$E_{AS}$	Single pulse avalanche energy (starting $T_j=25^\circ\text{C}$ , $I_D=I_{AS}$ , $V_{DD}=50$ V)	551	mJ

## 2 Electrical characteristics

( $T_{CASE}=25\text{ }^{\circ}\text{C}$  unless otherwise specified)

**Table 5. On/off states**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	$V_{GS} = 0$ , $I_D = 1\text{ mA}$	500			V
$I_{DSS}$	Zero gate voltage drain current	$V_{GS} = 0$ , $V_{DS} = 500\text{ V}$ $V_{GS} = 0$ , $V_{DS} = 500\text{ V}$ , $T_j = 125\text{ }^{\circ}\text{C}$			1 100	$\mu\text{A}$
$I_{GSS}$	Gate-body leakage current	$V_{DS} = 0$ , $V_{GS} = \pm 20\text{ V}$			$\pm 100$	nA
$V_{GS(\text{th})}$	Gate threshold voltage	$V_{DS} = V_{GS}$ , $I_D = 250\text{ }\mu\text{A}$	2	3	4	V
$R_{DS(\text{on})}$	Static drain-source on-resistance	$V_{GS} = 10\text{ V}$ , $I_D = 34\text{ A}$		0.035	0.043	$\Omega$

**Table 6. Dynamic**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$C_{iss}$	Input capacitance	$V_{DS} = 100\text{ V}$ , $f = 1\text{ MHz}$ , $V_{GS} = 0$	-	5790	-	pF
$C_{oss}$	Output capacitance		-	365	-	pF
$C_{rss}$	Reverse transfer capacitance		-	14	-	pF
$C_{oss\text{ eq.}}^{(1)}$	Equivalent output capacitance	$V_{GS} = 0\text{ V}$ , $V_{DS} = 0\text{ V}$ to $480\text{ V}$	-	1008	-	pF
$Q_g$	Total gate charge	$V_{DD} = 480\text{ V}$ , $I_D = 68\text{ A}$ , $V_{GS} = 10\text{ V}$	-	178	-	nC
$Q_{gs}$	Gate-source charge		-	28	-	nC
$Q_{gd}$	Gate-drain charge		-	95	-	nC
$R_g$	Gate input resistance	f=1 MHz gate DC bias=0 Test signal level = 20 mV open drain	-	2	-	$\Omega$

1.  $C_{oss\text{ eq.}}$  is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DS}$

**Table 7. Switching times**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 300 \text{ V}$ , $I_D = 32.5 \text{ A}$ $R_G = 4.7 \Omega$ $V_{GS} = 10 \text{ V}$	-	206	-	ns
$t_r$	Rise time		-	36	-	ns
$t_{d(off)}$	Turn-off delay time		-	40	-	ns
$t_f$	Fall time		-	27.5	-	ns

**Table 8. Source drain diode**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$I_{SD}$	Source-drain current Source-drain current (pulsed)		-		68	A
$I_{SDM}^{(1)}$	Source-drain current (pulsed)		-		272	A
$V_{SD}^{(2)}$	Forward on voltage	$I_{SD} = 68 \text{ A}$ , $V_{GS} = 0$	-		1.6	V
$t_{rr}$	Reverse recovery time	$I_{SD} = 68 \text{ A}$ , $dI/dt = 100 \text{ A}/\mu\text{s}$ $V_{DD} = 100 \text{ V}$	-	476		ns
$Q_{rr}$	Reverse recovery charge		-	10.5		nC
$I_{RRM}$	Reverse recovery current		-	44		A
$t_{rr}$	Reverse recovery time	$I_{SD} = 68 \text{ A}$ , $dI/dt = 100 \text{ A}/\mu\text{s}$ $V_{DD} = 100 \text{ V}$ , $T_j = 150 \text{ }^\circ\text{C}$	-	586		ns
$Q_{rr}$	Reverse recovery charge		-	15		nC
$I_{RRM}$	Reverse recovery current		-	51		A

1. Pulse width limited by safe operating area.
2. Pulsed: Pulse duration = 300  $\mu\text{s}$ , duty cycle 1.5%

## 2.1 Electrical characteristics (curves)

Figure 2. Safe operating area

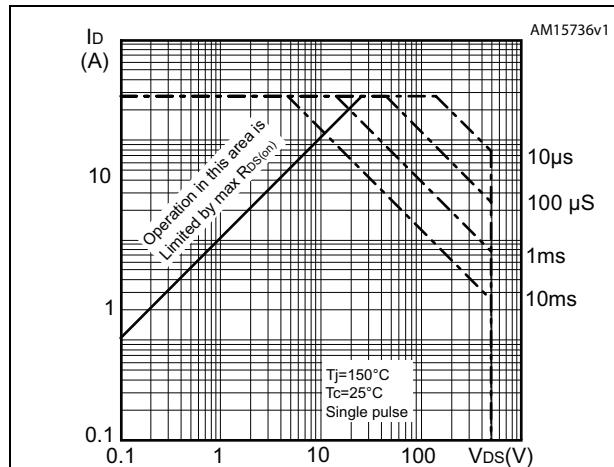


Figure 3. Thermal impedance

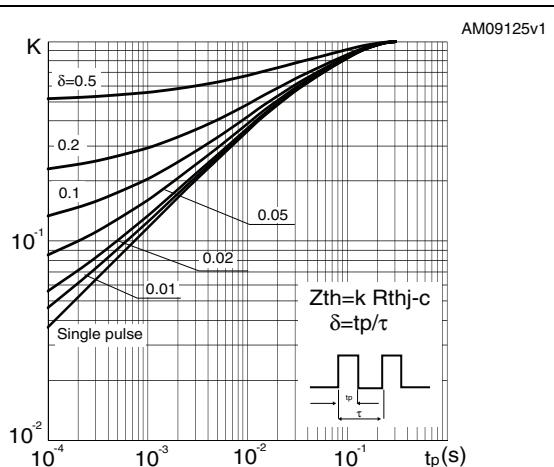


Figure 4. Output characteristics

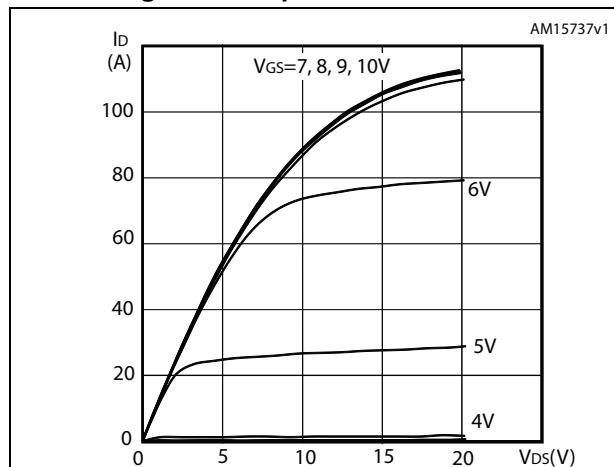


Figure 5. Transfer characteristics

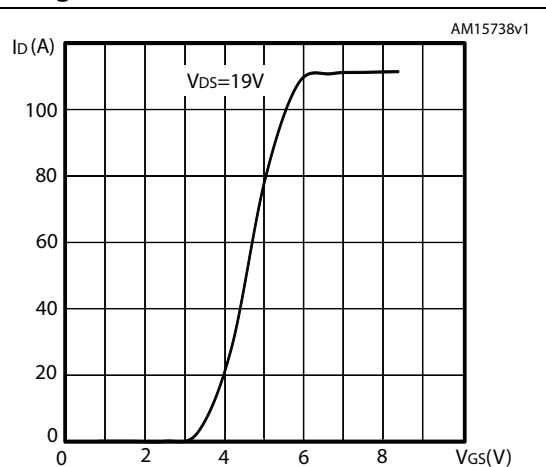
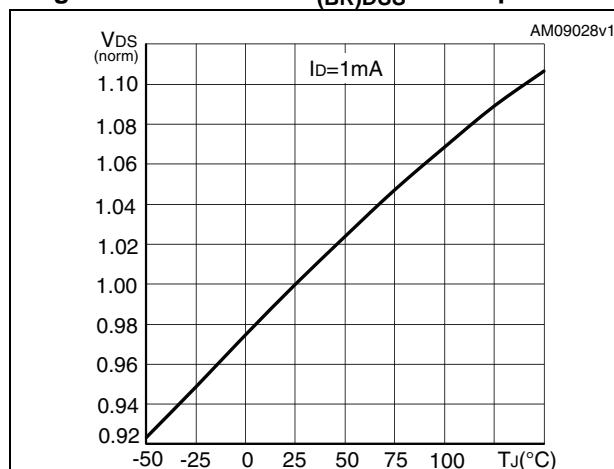
Figure 6. Normalized  $V_{(BR)DSS}$  vs temperature

Figure 7. Static drain-source on-resistance

